

Amendments to the Claims:

This listing of claims replaces all prior versions, and listings, of claims in this application.

Listing of Claims:

1. (Currently Amended) A method for testing a plurality of driver circuits on an array glass of an active matrix organic light emitting display (AMOLED) before organic light emitting diodes are implanted, each of the driver circuits including: a scan line, a data line, a power line, a first transistor, a second transistor and a first capacitor; the method comprising the steps of:

(a) repeating the steps (b) ~ (e) until a first signal and a second signal outputted from each of the driver circuits are retrieved;

(b) enabling one of the driver circuits ~~a target driver circuit~~ via the scan line;

(c) charging the first capacitor and retrieving the first signal from the data line when the first capacitor is discharged via the first transistor;

(d) disposing a conductive board above the array glass to form a second capacitor between the conductive board and the array glass;

(e) charging the second capacitor and retrieving the second signal from the power line when the second capacitor is discharged via the second transistor; and

(f) analyzing the first and second signals to determine the functionality of said one of the driver circuits ~~the target driver circuit~~.

2. (Original) The method of claim 1, wherein the step (c) further comprises:

(g) providing a high level voltage onto the data line to charge the first capacitor via the first transistor;

(h) providing a low level voltage onto the data line to discharge the first capacitor via the first transistor; and

(i) retrieving the first signal from the data line while the first capacitor is discharged.

3. (Original) The method of claim 1, wherein the step (e) further comprises:

(j) providing a high level voltage onto the power line to charge the second capacitor via the second transistor;

(k) providing a low level voltage onto the power line to discharge the second capacitor via the second transistor; and

(l) retrieving the second signal from the power line while the second capacitor is discharged.

4. (Original) The method of claim 1, wherein the first and second signals are a charge signal, a voltage signal or a current signal.

5. (Currently Amended) The method of claim 1, wherein the step (f) further comprises:

(m) respectively computing an average value of the first signals and an average value of the second signals of the driver circuits;

(n) determining whether the value of the first signal of each of the driver circuits is within $\pm 75\%$ of the average value of the first signals; and

(o) determining whether the value of the second signal of each of the driver circuits is within $\pm 75\%$ of the average value of the second signals;

wherein, if the value of the first signal of the driver circuit is within $\pm 75\%$ of the average value of the first signals, the first transistor and the first capacitor of said one of the driver circuits ~~the target driver circuit~~ has normal functionality, and if the value of the second signal of the driver circuit is within $\pm 75\%$ of the average value of the second signals, the second transistor of said one of the driver circuits ~~the target driver circuit~~ has normal functionality.

6. (Currently Amended) A apparatus for testing a plurality of driver circuits of an active matrix organic light emitting display (AMOLED) before organic light emitting diodes are implanted, the apparatus comprising:

a pixel selection device for selecting one of the driver circuits ~~target driver circuit~~;

a signal extractor for retrieving a signal; and

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a signal analyzer, connected to the signal extractor, for storing and
analyzing the signal to determine the functionality of said one of the driver
circuits ~~the target driver circuit~~.